

MCL FLASH TALKS Location: Basement, Characterization Commons

OL I LITO	There estation business, onarastorization commons
10:15 a.m.	Deposition and Characterization of Electronic Thin Films
10:30 a.m.	Surface Roughness Measurements: Choice of Technique and Analysis
10:45 a.m.	Imaging Delicate or Hydrated Materials in the Transmission Electron Microscope
11:15 a.m.	Characterization of Materials Using Thermal Analysis
11:30 a.m.	Characterization of Substrates and Thin Films Using X-rays
11:45 a.m.	Beyond the Diffraction Limit: Illuminating Surfaces and Interfaces with AFM-IR
2:00 p.m.	Characterization of Critical Mineral Phases in Mine Waste Products
2:15 p.m.	${\it Mapping Elemental Composition and Chemical Bonding at the Nanoscale Using TEM}\\$
2:30 p.m.	AFM in Action: Mapping the Nanoscale in Fluid
2:45 p.m.	$Morphometric\ Brochure: Image\ Transformations\ for\ 2D/3D\ Microstructure\ Analysis$
3:00 p.m.	Non-Destructive Depth Profiling of Organic Films using FTIR-ATR
3:15 p.m.	Utilization of GCIB for Mitigating Surface Contamination and Enabling Depth Profiling of Organic Films by XPS
3:30 p.m.	TGA and FTIR Coupled with Mass Spectrometry for Evolved Gas Analysis

3:45 p.m. New Courses and Industry-Focused Workshops on Materials Characterization

FOR COMPLETE DETAILS:



MATERIALS CHARACTERIZATION LAB TOURS

10:30 a.m. 10:45 a.m. 11:00 a.m. 11:15 a.m. 11:30 a.m. 2:15 p.m. 2:30 p.m. 3:00 p.m. 3:15 p.m. 3:30 p.m. 3:45 p.m.	SEM/FIB Lab Tour Surface Analysis Lab Tour AFM Mixed Reality Training Demo XRD: Wafer Defect Mapping Molecular Spectroscopy Tour Surface Metrology Lab Tour GIXRD: Thin Films and Bulk Materials XRD: Wafer Defect Mapping TEM Lab Tour GIXRD: Thin Films and Bulk Materials Thermal Analysis Lab Tour	N-031A N-031D N-030B N-030D N-007 N-030B N-030D N-30G N-008 N-007
--	--	--

TOURS and DFMOS

IOUK2 SUU DEMO2		
9:15 a.m.	TOUR: Silicon Carbide Innovation Alliance onsemi SiC3 (SCIA/SiC3) Depart from the 3rd Floor Commons	
10:00 a.m.	DEMO: 5G Characterization Techniques and Center for Dielectrics and Piezoelectrics (CDP) Technologies Room N-249	
10:15 a.m.	TOUR: Electronics Testing Lab Room N-221	
10:30 a.m.	DEMO (Technology Showcase): Synthetic Brochosomes: Novel Bioinspired Optical Materials Room N-252	
	TOUR: Optics Lab Room N-213 DEMO (Technology Showcase): Graphene Tongue (tentative Room N-226A)	
11:15 a.m.	TOUR: Nanofabrication Lab and Gowning Room Window Tour First Floor, Nanofabrication Lab Entrance	
11:30 a.m.	DEMO (Technology Showcase): In-field Plant Nutrient Sensor Room N-203B	
11:45 a.m.	TOUR: 2-Dimensional Crystal Consortium (2DCC) First Floor, 2DCC Hall	
2:00 p.m.	DEMO: 5G Characterization Techniques and Center for Dielectrics and Piezoelectrics (CDP) Technologies Room N-249	
2:15 p.m.	TOUR: Electronics Testing Lab Room N-221	
2:30 p.m.	DEMO (Technology Showcase): Synthetic Brochosomes: Novel Bioinspired Optical Materials Room N-252	
2:45 p.m.	TOUR: Optics Lab Room N-213	
3:00 p.m.	DEMO (Technology Showcase): Graphene Tongue (tentative Room N-226A)	
3:15 p.m.	TOUR: Nanofabrication Lab and Gowning Room Window Tour First Floor, Nanofabrication Lab Entrance	
3:30 p.m.	DEMO (Technology Showcase): In-field Plant Nutrient Sensor Room N-203B	
3:45 p.m.	TOUR: Silicon Carbide Innovation Alliance onsemi SiC3 (SCIA/SiC3) Depart from the 3rd Floor Commons	
4:00 p.m.	TOURS: Your choice of the Materials Characterization Lab (basement), Nanofabrication Lab (first floor), or the 2-Dimensional Crystal Consortium (first floor)	



